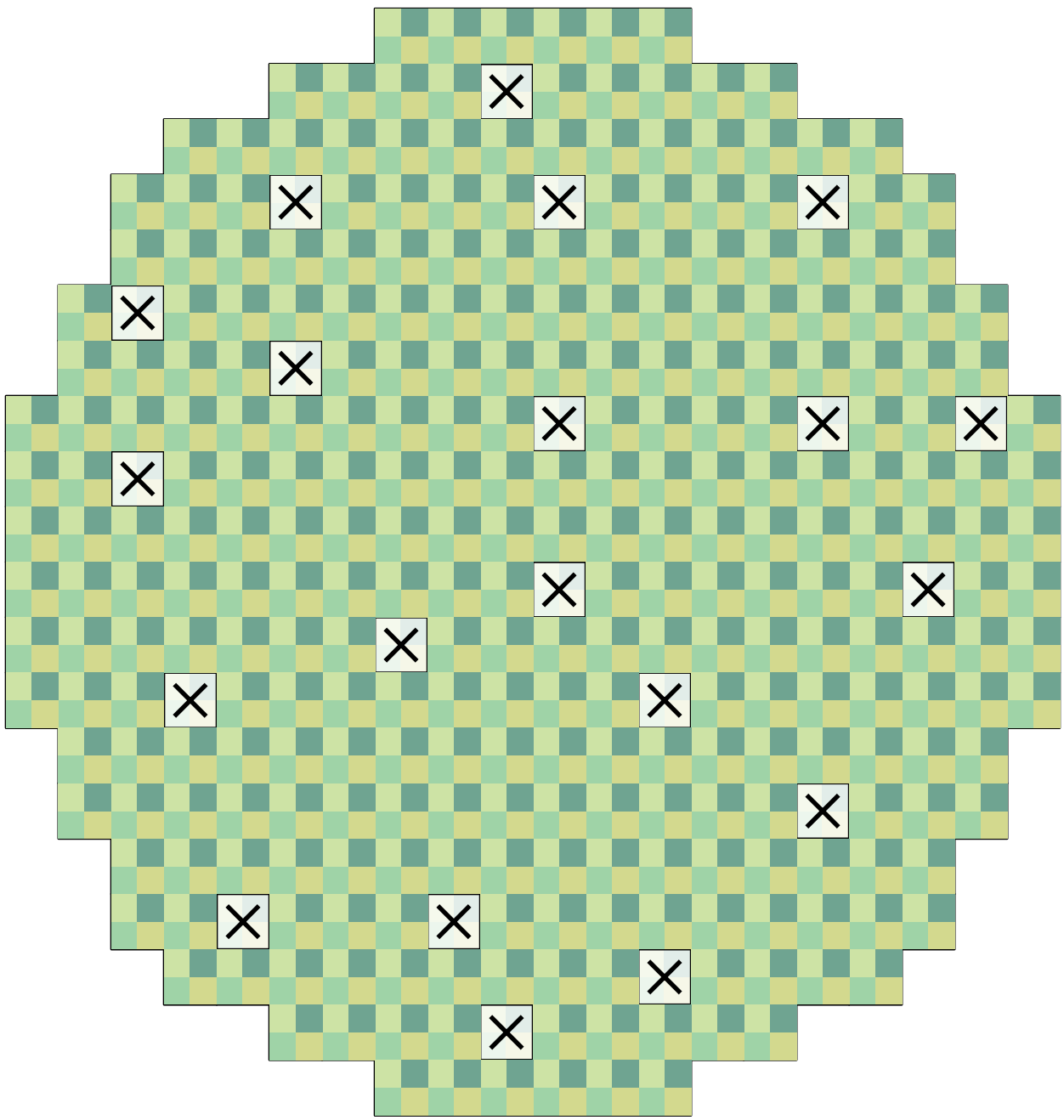




Die

× Measured dies



n_d Dies on the wafer

n'_d Measured dies

n_p Processing elements on a die

n'_p Measured processing elements on a die

n_t Time moments in the power profile

n'_t Measured time moments